

Seminar on New Opportunities for Testing and Certification in the Age of Technology

檢測認證在科技時代的新機遇研討會

Date 日期	18 March 2019 (Monday) 2019年3月18日(星期一)
Time 時間	2:30 p.m. to 5:25 p.m. 下午二時三十分至下午五時二十五分
Venue 地點	Conference Hall, 2/F, West Wing, Central Government Offices, 2 Tim Mei Avenue, Tamar, Hong Kong 香港添馬添美道2號政府總部西翼2樓會議廳

Supporting Organisations 支持機構

Programme 程序表

2:15 pm	Registration 登記
2:30 pm	Introduction and Group Photo with Speakers 簡介及與講者合照
2:40 pm	Smart Hong Kong 智慧香港 Speaker: Mr Tony Wong JP, Assistant Government Chief Information Officer (Industry Development), Office of the Government Chief Information Officer 講者: 政府資訊科技總監辦公室 助理政府資訊科技總監 (產業發展) 黃志光先生, JP
3:05 pm	Adoption of New Technologies for the Testing and Certification Sector 檢測認證業可應用的新技術 Speaker: Mr Simon Wong, Chief Executive Officer, Logistics and Supply Chain MultiTech R&D Centre 講者: 物流及供應鏈多元技術研發中心 行政總裁 黃廣揚先生
3:30 pm	Quantum Measurement Standards: New Trends in Electrical Metrology 量子測量標準：電學計量的新動向 Speaker: Dr Steven Yang, Senior Electronics Engineer, Standards and Calibration Laboratory, Innovation and Technology Commission 講者: 創新科技署 標準及校正實驗所 高級電子工程師 楊承隆博士
3:55 pm	Q&A session 問答環節
4:05 pm	Break 小休
4:25 pm	New Opportunities in Testing and Certification of Smart Products 智慧產品檢測認證的新機遇 Speaker: Mr Basil Wai, Chief Executive Officer, The Hong Kong Electronic Industries Association 講者: 香港電子業商會 行政總裁 衛紹邦先生
4:50 pm	Technology Voucher Programme 科技券計劃 Speaker: Ms Shirley Chan, Manager (Innovation and Technology Fund), Innovation and Technology Commission 講者: 創新科技署 經理 (創新及科技基金) 陳嘉慧女士
5:15 pm	Q&A session 問答環節
5:25 pm	Seminar ends 研討會完結

Note: The organisers reserve the right to alter the topic/content/speaker of the seminar programme without prior notice.
備註：主辦機構保留權利可更改調動研討會題目、內容及講者而不須先行通知。